

GE2761

N-CHANNEL ENHANCEMENT MODE POWER MOSFET

BVDSS	600/650V
RDS(ON)	1.0Ω
ID	10A

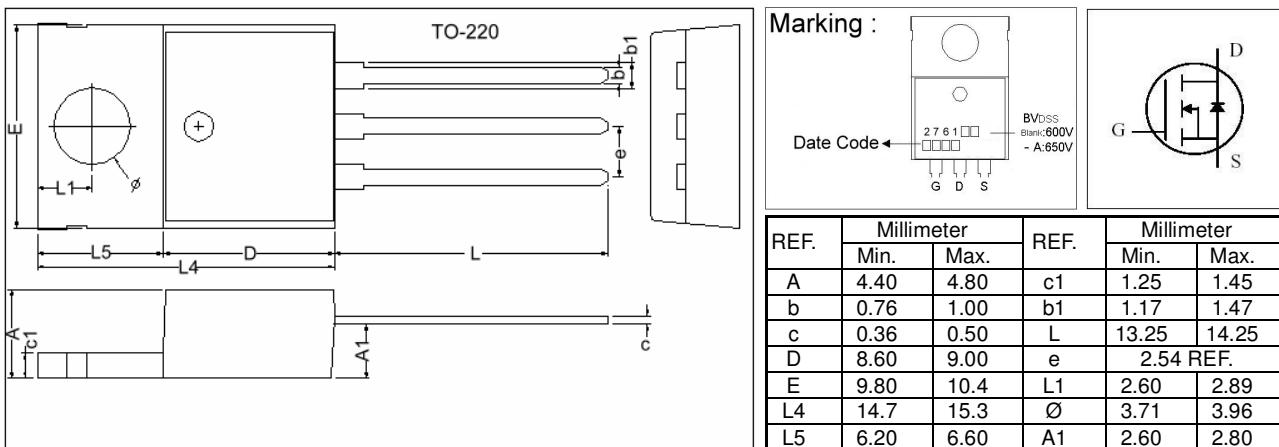
Description

The GE2761 series provide the designer with best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The through-hole version (TO-220) is available for low-profile applications and suited for low voltage applications such as DC/DC converters.

Features

- *Low On-resistance
- *Simple Drive Requirement
- *RoHS Compliant
- *Fast Switching Characteristic

Package Dimensions**Absolute Maximum Ratings**

Parameter	Symbol	Ratings	Unit
Drain-Source Voltage	-A	V _{DS}	600/650 V
Gate-Source Voltage		V _{GS}	±30 V
Continuous Drain Current, V _{GS} @10V	I _D @T _c =25°C	10 A	
Continuous Drain Current, V _{GS} @10V	I _D @T _c =100°C	4.4 A	
Pulsed Drain Current ¹	I _{DM}	18 A	
Total Power Dissipation	P _D @T _c =25°C	104 W	
Linear Derating Factor		0.8 W/°C	
Avalanche Current	I _{AR}	10 A	
Operating Junction and Storage Temperature Range	T _j , T _{stg}	-55 ~ +150 °C	

Thermal Data

Parameter	Symbol	Value	Unit
Thermal Resistance Junction-case Max.	R _{thj-c}	1.2 °C/W	
Thermal Resistance Junction-ambient Max.	R _{thj-a}	62 °C/W	

Electrical Characteristics($T_j = 25^\circ\text{C}$ Unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Drain-Source Breakdown Voltage	BV_{DSS}	600	-	-	V	$\text{V}_{\text{GS}}=0, \text{I}_D=250\mu\text{A}$ -
		650	-	-	V	$\text{V}_{\text{GS}}=0, \text{I}_D=250\mu\text{A}$ A
Breakdown Voltage Temperature Coefficient	$\Delta \text{BV}_{\text{DSS}} / \Delta T_j$	-	0.6	-	V/ $^\circ\text{C}$	Reference to 25°C , $\text{I}_D=1\text{mA}$
Gate Threshold Voltage	$\text{V}_{\text{GS(th)}}$	2.0	-	4.0	V	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_D=250\mu\text{A}$
Forward Transconductance	g_{fs}	-	4.5	-	S	$\text{V}_{\text{DS}}=10\text{V}, \text{I}_D=3.5\text{A}$
Gate-Source Leakage Current	I_{GSS}	-	-	± 100	nA	$\text{V}_{\text{GS}}= \pm 30\text{V}$
Drain-Source Leakage Current($T_j=25^\circ\text{C}$)	I_{DSS}	-	-	10	μA	$\text{V}_{\text{DS}}=600\text{V}, \text{V}_{\text{GS}}=0$
Drain-Source Leakage Current($T_j=150^\circ\text{C}$)		-	-	100	μA	$\text{V}_{\text{DS}}=480\text{V}, \text{V}_{\text{GS}}=0$
Static Drain-Source On-Resistance	$\text{R}_{\text{DS(ON)}}$	-	-	1.0	Ω	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_D=3.5\text{A}$
Total Gate Charge ³	Q_g	-	53	85	nC	$\text{I}_D=10\text{A}$ $\text{V}_{\text{DS}}=520\text{V}$ $\text{V}_{\text{GS}}=10\text{V}$
Gate-Source Charge	Q_{gs}	-	10	-		
Gate-Drain ("Miller") Change	Q_{gd}	-	15	-		
Turn-on Delay Time ³	$\text{T}_{\text{d(on)}}$	-	16	-	Ns	$\text{V}_{\text{DD}}=320\text{V}$ $\text{I}_D=10\text{A}$ $\text{V}_{\text{GS}}=10\text{V}$ $\text{R}_G=10\Omega$ $\text{R}_D=30\Omega$
Rise Time	T_r	-	20	-		
Turn-off Delay Time	$\text{T}_{\text{d(off)}}$	-	82	-		
Fall Time	T_f	-	36	-		
Input Capacitance	C_{iss}	-	2770	4430	pF	$\text{V}_{\text{GS}}=0\text{V}$ $\text{V}_{\text{DS}}=15\text{V}$ $f=1.0\text{MHz}$
Output Capacitance	C_{oss}	-	320	-		
Reverse Transfer Capacitance	C_{rss}	-	8	-		

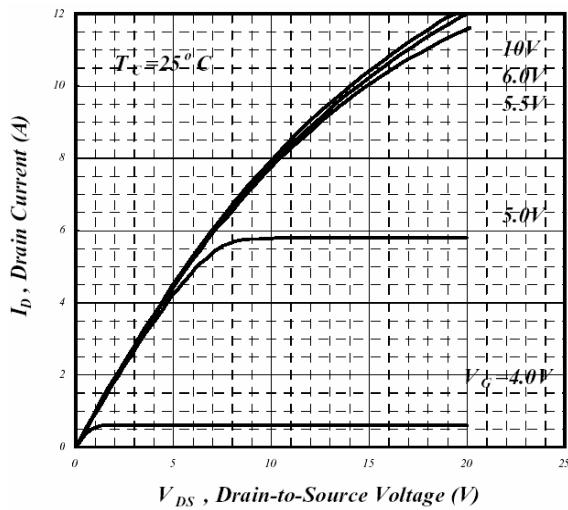
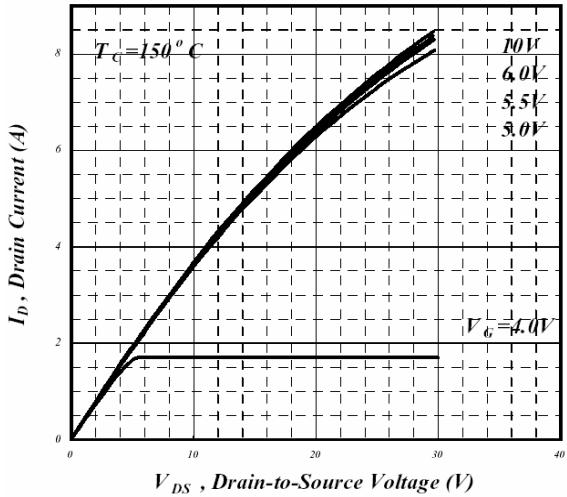
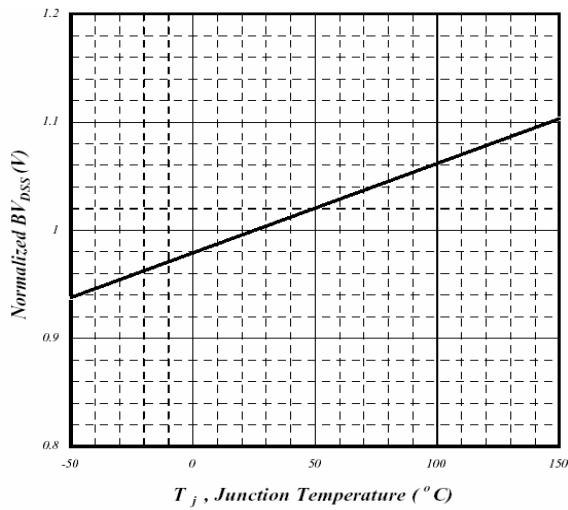
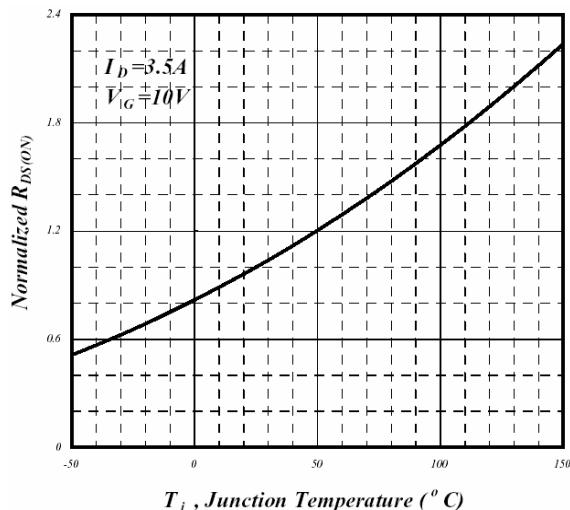
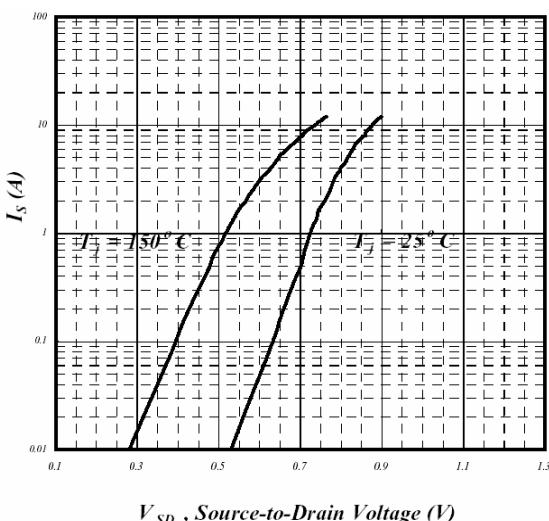
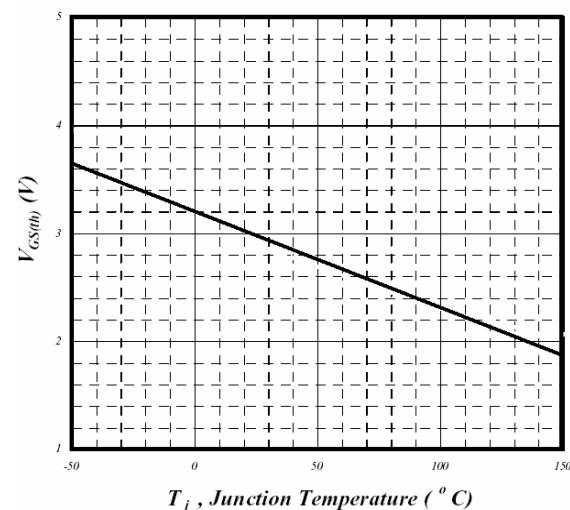
Source-Drain Diode

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Forward On Voltage ³	V_{SD}	-	-	1.5	V	$\text{I}_S=10\text{A}, \text{V}_{\text{GS}}=0\text{V}, \text{T}_j=25^\circ\text{C}$
Reverse Recovery Time ³	T_{rr}	-	610	-	ns	$\text{I}_S=10\text{A}, \text{V}_{\text{GS}}=0\text{V}$ $d\text{I}/dt=100\text{A}/\mu\text{s}$
Reverse Recovery Charge	Q_{rr}	-	8.64	-	μC	

Notes: 1. Pulse width limited by safe operating area.

2. Staring $\text{T}_j=25^\circ\text{C}$, $\text{V}_{\text{DD}}=50\text{V}$, $\text{L}=1.2\text{mH}$, $\text{R}_G=25\Omega$, $\text{I}_{\text{AS}}=10\text{A}$.

3. Pulse width $\leq 300\text{us}$, duty cycle $\leq 2\%$.

Characteristics Curve**Fig 1. Typical Output Characteristics****Fig 2. Typical Output Characteristics****Fig 3. Normalized BV_{dss} v.s. Junction Temperature****Fig 4. Normalized On-Resistance v.s. Junction Temperature****Fig 5. Forward Characteristics of Reverse Diode****Fig 6. Gate Threshold Voltage v.s. Junction Temperature**

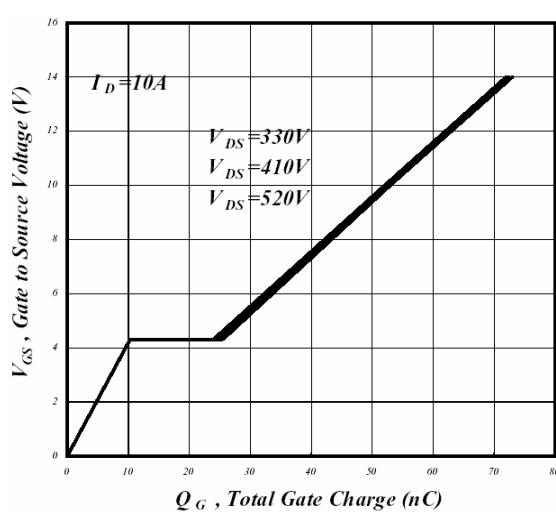


Fig 7. Gate Charge Characteristics

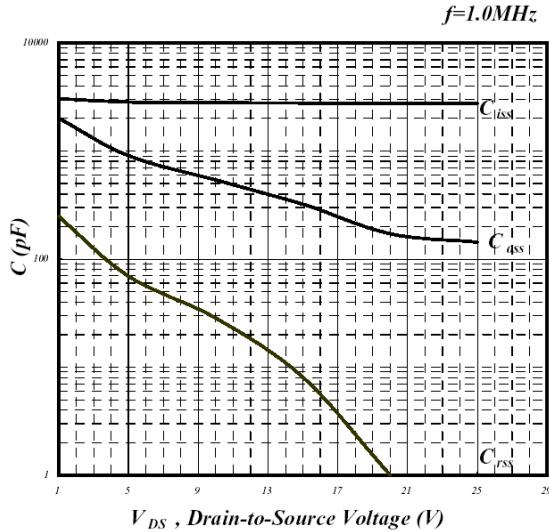


Fig 8. Typical Capacitance Characteristics

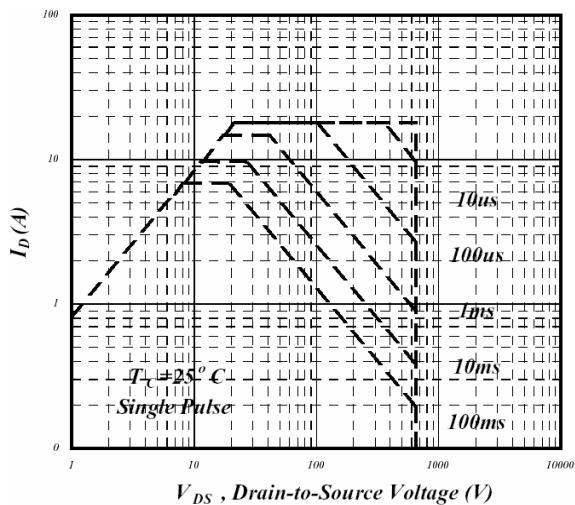


Fig 9. Maximum Safe Operating Area

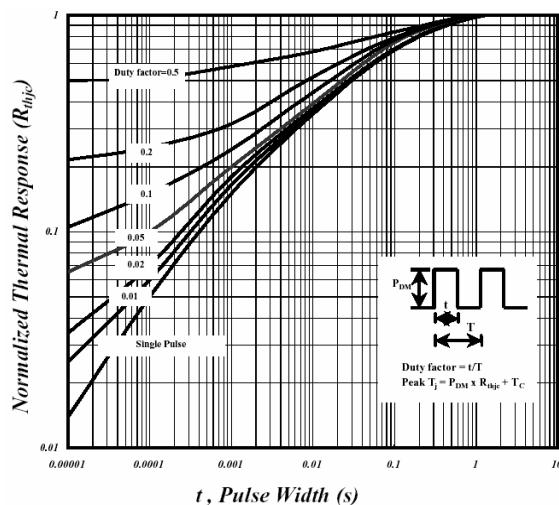


Fig 10. Effective Transient Thermal Impedance

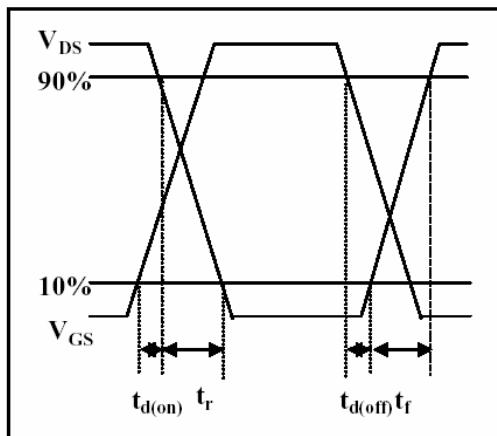


Fig 11. Switching Time Waveform

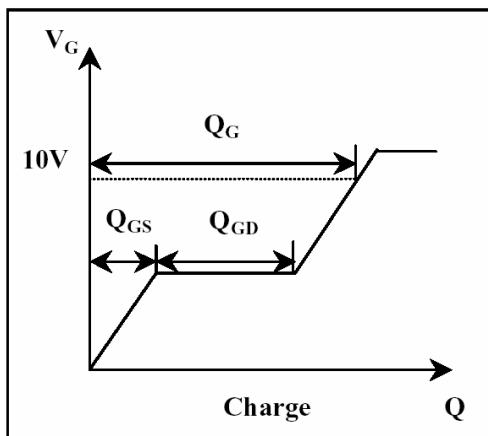


Fig 12. Gate Charge Waveform

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- Head Office And Factory:**
- Taiwan:** No. 17-1 Tatung Rd. Fu Kou Hsin-Chu Industrial Park, Hsin-Chu, Taiwan, R. O. C.
TEL : 886-3-597-7061 FAX : 886-3-597-9220, 597-0785
 - China:** (201203) No.255, Jiang-Jiang Tsai-Lueng RD. , Pu-Dung-Hsin District, Shang-Hai City, China
TEL : 86-21-5895-7671 ~ 4 FAX : 86-21-38950165